

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant(s) : Aaron PARTRIDGE et al.
 Serial No. : 10/713,172
 Filing Date : November 14, 2003
 For : CRACK AND RESIDUE FREE CONFORMAL
 DEPOSITED SILICON OXIDE WITH
 PREDICTABLE AND UNIFORM ETCHING
 CHARACTERISTICS
 Examiner : Francis P. Smith
 Group Art Unit : 4151
 Confirmation No. : 9823
Customer No. : **26646**

Mail Stop Amendment
 Commissioner for Patents
 P.O. Box 1450
 Alexandria VA 22313-1450

I hereby certify that this correspondence is being electronically transmitted to the United States Patent and Trademark Office via the Office electronic filing system on April 17, 2008

Signature: /Elizabeth Tretter/

AMENDMENT

SIR:

In response to the Office Action of January 18, 2008 (the three-month response date for is April 18, 2008), please reconsider the above-identified application based on the following.

Amendments to the Specification begin on page 2 of this paper.

Amendments to the Claims are reflected in the listing of the claims which begins on page 3 of this paper.

Remarks begin on page 11 of this paper.